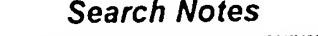


<b>Search Notes</b> 	<b>Application/Control No.</b> 10/661,579	<b>Applicant(s)/Patent under Reexamination</b> NAKAGAWA ET AL.
<b>Examiner</b> Diem Tran	<b>Art Unit</b> 3748	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner